Abstract

The invention relates to a process to examine at least one object, whereby properties of the object are detected at different times within a spatial-frequency space formed by spatial frequencies.

According to the invention, the process is carried out in such a way that consecutive images are recorded in overlapping areas of the spatial-frequency space and, additionally, in areas of the spatial-frequency space that differ from each other.

List of reference numerals:

1 central area

10 additional areas of the spatial-frequency space

20 additional areas of the spatial-frequency space

30 additional areas of the spatial-frequency space